

Model 2650

Test wire harnesses and components with easily distributed test modules.

- Innovative, modular design
- Distributed or centralized configuration
- · Minimizes test adapter length
- · Scalable to future needs
- Reconfigurable for multiple applications
- Cost effective for small or large test requirements



Model 2650.MTA Modular Test Analyzer



Innovative
Scalable
Open Architecture
Reconfigurable
Cost Effective



Dis•trib•u•ted Switch•ing: configuring testers in a manner that allows switch modules to be placed closer to your unit under test, eliminating cumbersome adapter cables and providing added mobility and flexibility.

Cost Effective

 Keeping the switching near the product means you don't need long and expensive test adapter cables.

Saves Time

• Short interfaces are simpler to handle and install.

Reconfigurable

 Reconfigure a station by adding switching modules for a particular test.

Maximizes Space

 Reduce the storage required for test adapters and eliminate long cables with optional probe connections in each switching module.

Simplified Interface

 Access any point that requires power with optional External Energization built into each switching module.

Random Hookup

 With either a bar code scan or a keyed code in each connector, you can connect cables in any order to any convenient connection.

Open Architecture

 Easily incorporate new technology into an existing framework to adapt to new innovations.

Scalable

 From the smallest subassemblies to full harness and final assembly testing, the 2650.MTA delivers a full range of testing options.





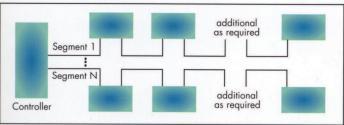


Con-fig-u-ra-tions: arrangement of switching modules to accommodate changing test conditions in the most efficient manner possible.



Test Station Controller. The Model 2650.MTA's test station controller includes the microprocessor driven control assembly and the DIT-MCO SMU (Standard Measurement Unit) instrumentation. Interchangeable control and instrumentation printed circuit board assemblies simplify maintenance.

Racks or Modules. Choose either concentrated test banks where large number of test points are needed or utilize distributed switching in areas where there are fewer terminations or when space is limited.



Multiple Segments. Switching modules can be added for up to 15,000 test points per segment and connect to the controller in segments of up to 75 meters (250 feet). Each module receives operating power from the daisy chain control cable, eliminating additional power cords and AC sockets.

Interface Connections



ZIF 150 Point



D-Sub 50 Pin



DIN 41612



EasyConnect

Fi•nal As•sem•bly Test•ing: using the Model 2650 switching modules in combination to provide concentrated test banks of switching where a large number of test points are needed or distributed switching for fewer test points in widely separated zones of the product under test.



Har•ness/Pa•nel Test•ing: using the Model 2650 in harness or subassembly test benches to support multiple test stations from a single controller.

